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U.S. UTILITY Patern Application

PATENT DATE

SCANNED

Q.A. 65

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/678652		436		1655	£-76
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Method of inspecting a DNA chip and an apparatus thereof

TILE

PTO-2040 12/99

PATENT NUMBER

ISSUING CLASSIFICATION									
ORIGINAL		CROSS REFERENCE(S)							
CLASS SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
INTERNATIONA	L CLASSIFICATION								
			Continued on Issue Slip Inside File Jacket						

TERMINAL	≡	DRAWINGS		CLAIMS ALLOWED	
L.J DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
☐ The term of this patent				NOTICE OF ALI	LOWANCE MAILED
subsequent to (date) : has been disclaimed.	(Assistant	Examiner)	(Date)		
The term of this patent shall not extend beyond the expiration date of U.S Patent. No.				ISS	UE FEE
				Amount Due	Date Paid
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this patent have been disclaimed.	(Legal Instruments Examiner)		(Date)		
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